

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. <b>262666US0PCT</b>		SERIAL NO. New U.S. PCT Application Based on PCT/JP02/05920  <div style="font-size: 1.5em; font-weight: bold;">10/517375</div>			
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yoko HANADA, et al.		FILING DATE Herewith		GROUP	

  

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						

  

FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
/J.P./	AK	2002-179535	06/26/02	JP (with English abstract)		NO
<div style="font-size: 2em;">↓</div>	AL	9-194335	07/29/97	JP (with English abstract)		NO
	AM	9-151119	06/10/97	JP (with English abstract)		NO
	AN	2000-143458	05/23/00	JP (with English abstract)		NO
	AO	2000-128740	05/09/00	JP (with English abstract)		NO
	AP	9-183854	07/15/97	JP (with English abstract)		NO
	AQ	93 10748	06/10/93	WO (with English abstract)		NO
	AR	92 06899	04/30/92	WO (English abstract only)		NO
	AS	94 16677	08/04/94	WO (with English abstract)		NO
	AT	0 078 597	05/11/83	EP		NO
	AU	2001-513534	09/04/01	JP		NO
/J.P./	AV	99 09939	03/04/99	WO (with English abstract)		NO

  

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)		
/J.P./	AW	Koushouhin Kagaku, pages 130-131
/J.P./	AX	Koushouhin Kagaku, pages 308-311
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner      /Jeffrey Palenik/	Date Considered    10/30/2007
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\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yoko HANADA, et al.			
				FILING DATE June 9, 2005		GROUP 1615	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
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	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/J.P./	AO	4-230615	08/19/1992	JAPAN (English Abstract attached)			X
/J.P./	AP	5-70327	03/23/1993	JAPAN (English Abstract attached)			X
/J.P./	AQ	5-238920	09/17/1993	JAPAN (English Abstract attached)			X
/J.P./	AR	8-208439	08/13/1996	JAPAN (English Abstract attached)			X
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Jeffrey Palenik/					Date Considered 10/30/2007		
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